



Operations Report

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CDF Weekly Meeting



Store summary

Date	Inst Lum (initial)	Int Lum (live)	ϵ	Comments
Mo 7/7	32.6e30	702.3	73.6%	Human error, TDC problem
Tu 7/8	33.6e30	1259.7	87.6%	CAEN crate failures in plug, Si
We 7/9	35.3e30	1321.1	89.1%	Clock glitch, 2 Si CAEN crate failures

Few stores as accelerator complex had a truly astounding number of problems over the weekend



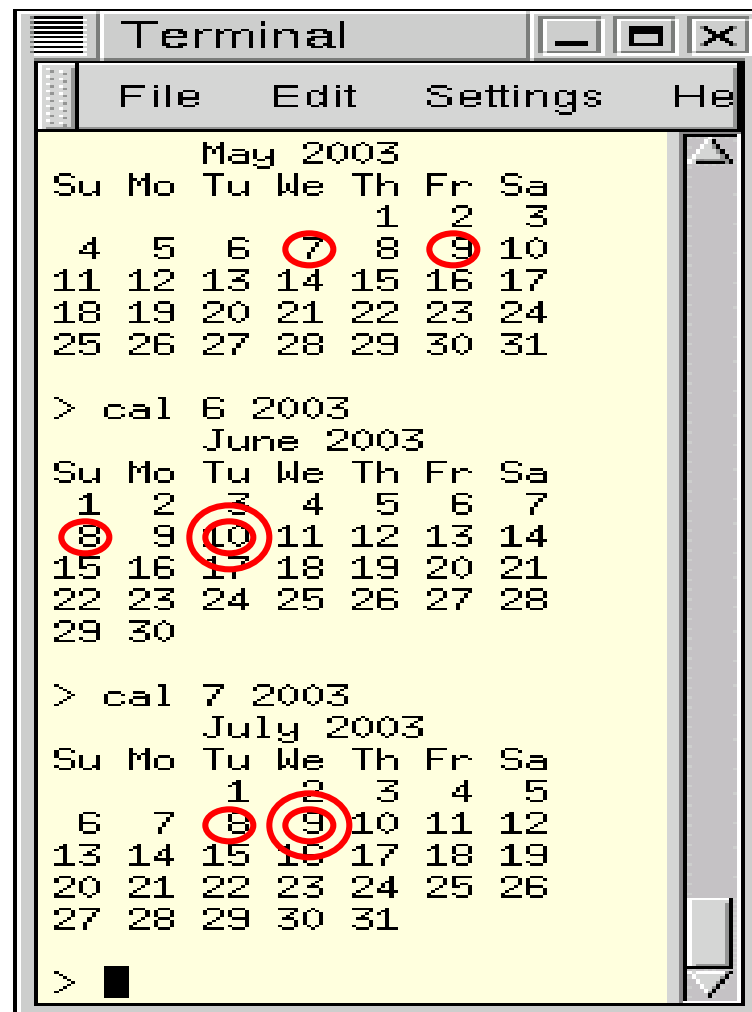
CDF's down time

- “Human error”
 - Housecleaning: old versions of Java were deleted, but EVB cleanup script had old version secretly hardwired in
 - Resolution: EVB will use “current default” from now on
- Global TDC done timeouts
 - Usually recoverable by “shepherding,” but not this time
 - Expert tried several TDC reseats, but in the end TDC had to be swapped out
- Plug HV
 - Trip that could only be recovered by power-cycling CAEN crate (3rd in “list of things to try”)
- Clock Glitch
 - Lightning strike likely culprit
 - Actually the quickest recovery from a clock problem I’ve ever seen (20 mins)
 - Switching from cable TV to optical link will robustify the clock



CDF down time, cont.

- Si CAEN crate communication failures
 - Distributed across all 16 crates
 - Not correlated with any losses (SEUs)
 - Come in weird periodic waves →
- COT HV trips
 - Two in SL3 quad C this week – lowered by 40V in hopes of surviving 'til shutdown





Activities/Plans

- Majority of data taken this week has included compressed COT/Si data (as a copy)
 - Trying to find any low-rate bugs
- Two accesses used (not requested)
 - Two silicon ladders fixed
- L2 composite triggers tested
- End-of-store-tests that have been requested
 - “Bring tha noise” on silicon --- simulate what life would be like with no SVX upgrade and several inverse femtobarns
 - Diffractive trigger test
 - Test scheme where SVT only acts when the appropriate L1 bit has fired
 - High rate EVB test
 - XFT test???
 - New TDC code test